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## RADES PATENT DOCUMENTS

Examiner			Patented or	
Initials	Cite No.	Document No. & Kind Code (if known)	Publication Date	Name of Patentee or Applicant
	AA			
	AB			
	AC			
	AD			
	AE			
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	AI			
	AJ			
	AK			

## FOREIGN PATENT DOCUMENTS

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Initials	Cite No.	Document No. & Kind Code (if known)	Publication Date	Name of Patentee or Applicant	Translated?
DT	BA	JP 08-026157 A	01/30/1996	Hayashi et al.	Abstract
DT	BB	JP 2001-171575 A	06/26/2001	Futami et al.	Abstract
M	BC	JP 2002-099357 A	04/05/2002	Nakamura	Abstract
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	BE				
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## **OTHER ART**

Examiner		AUTHOR, Title of Article, Book, Magazine, date, volume-issue no., publisher, city and/or	
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	CA		
	CB		

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